An investigative study into the sensitivity of different partial discharge φ-q-n pattern resolution sizes on statistical neural network pattern classification

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7 Abstract

This paper investigates the sensitivity of statistical fingerprints to different phase resolution 8 (PR) and amplitude bins (AB) sizes of partial discharge (PD) φ -q-n (phase-amplitude-9 number) patterns. In particular, this paper compares the capability of the nsemble neural 10 11 network (ENN) and the single neural network (SNN) in recognizing and distinguishing different resolution sizes of φ -q-n discharge patterns. The training fingerprints for both the 12 13 SNN and ENN comprise statistical fingerprints from different φ -q-n measurements. The result shows that there exists statistical distinction for different PR and AB sizes on some of 14 the statistical fingerprints. Additionally, the ENN and SNN outputs change depending on 15 training and testing with different PR and AB sizes. Furthermore, the ENN appears to be 16 more sensitive in recognizing and discriminating the resolution changes when compared with 17 the SNN. Finally, the results are assessed for practical implementation in the power industry 18 and benefits to practitioners in the field are highlighted. 19

Keywords— classification, partial discharge and ensemble neural network, phase resolution and amplitude bin sizes.

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29 Abbreviations

30	NN	neural networks
31	SNN	single neural network
32	ENN	ensemble neural network
33	PR	phase resolution
34	AB	amplitude resolution
35	PD	partial discharge
36	HV	high voltage
37	CI	confidence intervals
38	φ-q-n	phase-amplitude-number
39	IEC	international electrotechnical commission
40	Hn(ϕ)	pulse count distribution
41	Hqn(q)	mean pulse-height
42	Hn(q)	amplitude-number
43	DEM	dynamically weighted ensemble network
44	DAN	dynamically averaged network
45	sk	skewness
46	ku	kurtosis
47	Q	discharge factor
48	сс	cross-correlation
49	тсс	modified cross-correlation
50	μs	average recognition rates of the SNN
51	μ_E	mean of the recognition efficiencies of the ENN
52	σ_S	variance of the recognition efficiencies of the SNN
53	σ_E	variance of the recognition efficiencies of the ENN
54	SEM	standard error of the mean
55	σ_{SM}	SEM of the recognition efficiencies of the SNN
56	σем	SEM of the recognition efficiencies of the ENN
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59 **1. Introduction**

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Partial discharge (PD) measurements have been a vital index for evaluating electrical 61 insulation degradation under high voltage (HV) electrical stress. It is important to understand 62 the extent of insulation damage and the nature of an insulation fault through PD measurement 63 64 for reliable insulation assessment. PD is an electrical discharge that occurs within a localised position of the electrical insulation when the insulation starts to degade [1]. If PD is detected, 65 66 it is also essential to recognize the nature and extent of the insulation defect, since each particular PD fault has a distinct footprint pattern of discharge behaviour [2,3,4,5]. Over the 67 years, several techniques have been investigated for use in PD pattern recognition. These 68 include the neural network (NN)[1,6,7,8,9], fuzzy logic controllers [10], data mining 69 approaches [11], support vector machines [12], hidden markov models [13] and adaptive 70

71 resonance theory [14]. Such research has recorded successful recognition performance with recognition rates reaching as high as 90% for unseen PD fault examples. Thesuccesful rates 72 eere achieved through several feature extraction techniques when applied to acquire training 73 74 and testing parameters for the pattern recognition tools. Statistical fingerprints from φ -q-n (phase-amplitude-number) patterns have been the most widely applied measures [1,15] for 75 PD recognition because of their capability for well-defined PD pattern quantification. 76 However, due to the complex nature of PD, coupled with degradation consequences, these 77 statistical fingerprints may show different characteristics over different insulation degradation 78 79 periods [16].

To improve the reliability and uniqueness of statistical fingerprints in being able to identify 80 81 PD defects, Gulski and Krivda [1] made significant efforts by establishing 95% mean confidence intervals (CI) for statistical features for classes of several artificially created two 82 83 electrode PD defects. The statistical mean error tolerances as obtained by Gulski and Krivda were based on fixed PR and AB sizes of the φ -q-n patterns and were determined from a series 84 85 of measurements ranging from 4 to 23 separate φ -q-n patterns for the same type of PD fault. In this context, the research question is posed in relation to evaluating the sensitivity of 86 87 statistical fingerprints for different φ -q-n PR and AB changes and how such variations in PR 88 and AB could potentially influence classification outcomes when pattern recognition tools are applied. Moreover, further research is important because different measuring instruments 89 may have different resolution settings for the φ -q-n pattern assessmentand thus training data 90 91 captured using a different set-up may vary from the actual measurement which may lead to an unreliable classification outcome. 92

In an attempt to address these situations, this paper aims at determining the sensitivity of 93 statistical fingerprints as a function of PR and AB sizes of the φ -q-n patterns. For each 94 statistical fingerprint defining a particular PD defect, statistical 95% mean error tolerances for 95 96 different resolution sizes are compared, quantified and evaluated. To achieve this, a number 97 of φ -q-n samples (ranging from 40 to 215) for different PD fault scenarios are considered. This is used to quantify the statistical behaviour as a function of PR or AB and provide 98 99 potentially an improved classification tool since large datasets of the same PD sources are 100 considered. Due to the success of the ensemble neural network (ENN) in classifying PD 101 patterns [15], this paper extensively compares the ENN's capability with the single neural network (SNN) in classifying and discriminating different resolution sizes of the φ -q-n 102 103 patterns over several statistical merit indicators. This is important to determine and compare

the statistical error bounds recognition rates of the SNN and ENN for different resolutionsizes.

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107 2. Experimental set-up and feature extraction

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109 2.1Artificially created PD faults

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To obtain the PD samples for investigation, four different fault geometries were fabricated in 111 a HV laboratory to simulate PD faults currently occurring in practice (see Fig. 1). These 112 comprise corona in air and oil, surface discharges in air and oil, single voids and an electrode 113 114 bounded cavity. The corona discharge model is a point-plane arrangement. A needle of length 3 cm and tip radius of approximately 10 µm is connected to the HV, while an electrode is of 115 60 mm in diameter is connected to the ground. The voids are of 0.6 mm diameter and 50 µm 116 thickness, created at the center of the middle layer of 7 poly-ethylene-terephthalate (PET) 117 118 samples. The surface discharge in air was simulated by placing a small brass ball of 55 mm diameter on perspex of geometrical size 65 mm x 65 mm x 8 mm. The surface discharge in 119 120 oil is simulated by a pressboard embedded in a container with Castrol insulating oil [15]. A 121 needle was placed at a predetermined angle to the surface of the pressboard and 45 mm distance from a block earth electrode, also placed on the pressboard surface[17]. Examples of 122 the φ -q-n patterns for several of the considered PD fault geometries are shown in Fig. 2. For 123 corona in air, the positive and negative φ -q-n patterns have been separated for improved 124 visibility of the positive corona discharges characterized by their small repetition rate. 125

Fig 1: Simulated PD faults: a) surface discharge in air, b) single void in PET, c) corona in airand d) surface discharges in oil.

The experimental conditions and test φ -q-n samples generated for each PD fault type is shown in Table 1. For each fault, relatively large φ -q-n samples were generated so as to determine reliable 95% mean CI limits for improved evaluation by the SNN and ENN. For corona in air, measurements were taken at several voltages over two gap distances of 5mm and 10mm because of the discharge behaviour of the positive corona discharge which have low repetition rate and higher amplitude [18]. They are then combined to form the φ -q-n corona set for SNN and ENN evaluation.

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Fig.2: Example of the φ -q-n patterns for the PD faults considered.

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- Table 1: PD fault types with the test voltages and corresponding φ -q-n samples.

139 **2.2 Experimental test arrangement**

140 The PD measurement process was performed in accordance with the IEC60270 PD 141 standard[19]. The PD detection system produces a power cycle which is used to synchronize 142 real time φ -q-n patterns and possess functions for automatic data logging these patterns at 143 different time periods as well as controlling changes in PR and AB sizes. This is important 144 for the work presented in this paper, as several experiments require longer stressing periods 145 and data is required to be captured and stored systematically over certain resolution size for 146 analysis. PD calibration was carried out for PD apparent charge determination.

147 **2.3** Choice of statistical fingerprints for PD analysis

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For φ -q-n evaluation, statistical fingerprints have been widely applied because of their capability for well-defined pattern quantification [1,15]. In order to simplify the φ -q-n analysis, statistical fingerprints are usually extracted from 2D plots derived from the φ -q-n patterns. The key 2D distributions of interest are the pulse count $H_n(\varphi)$, mean pulse-height $H_{qn}(\varphi)$ and amplitude number $H_n(q)$ plots. These plots are presented in both the positive (+) and negative half power cycles (-).

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Similar to other literature [4], this paper applies 15 statistical parameters that serve as input 156 fingerprints for training and testing both the ENN and SNN. These include the skewness (*sk*) 157 and kurtosis (ku) of the $H_{qn}(\varphi)+$, $H_{qn}(\varphi)-$, $H_n(q)+$, $H_n(\varphi)-$ and $H_n(\varphi)-$ distributions, 158 the cross-correlation (cc), discharge factor (Q) and modified cross-correlation (mcc). 159 Definitions of these statistical parameters are available in [1] and their mathematical 160 expressions are shown in Table 2. In this table, μ represents the mean value, σ is the standard 161 deviation, *n* represents the size of the data and P_i is the probability of the discrete values x_i 162 and y_i . Q_s^+ and Q_s^- represent the sum of discharge magnitudes in the positive and negative 163 half cycles while N_{s}^{+} and N_{s}^{-} represent the number of discharges in the positive and negative 164 half power cycle. 165

Table 2: Mathematical expressions of statistical fingerprints

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3. Description of the ENN algorithm

171 An ENN is a learning model comprising a limited number of NNs trained for the same task [20]. The ENN can enhance the generalization performance of the SNN by simply training a 172 number of SNNs and combining their output predictions. Diverse types of ENN architectures 173 have evolved. These include the simplest ENN, The Naive classifier technique, the 174 generalised ENN and the dynamically weighted ensemble method (DEM) [21]. The latter 175 determines the neural network weight at any time the network is estimated and provides the 176 best performance at any instant [21]. The weight is proportional to the certainty of the 177 individual NN prediction and this certainty evaluates how close the output is to any known 178 179 target value. The prediction of the NN can be regarded to be a probability of any occurrence. For example, assume that b = f(a) is the output of the network and a represents the input 180 variables. If b approaches unity, it is more certain that it belongs to a certain class. When b is 181 close to 0, it is certain that this instance is not in that particular class. The certainty of the NN 182 is computed as follows[10], 183

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$$c(b) = \begin{cases} b & \text{if } b \ge 0.5\\ 1-b & \text{otherwise} \end{cases}$$
(1)

185 The prediction of the Dynamically Averaged Network (DAN) can be computed as follows:

 $f_{DAN} = \sum_{i=1}^{n} w_j f_j(a)$

(2)

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191 where the weights w_i are defined based on

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193 $w_{j} = \frac{c(f_{j}(a))}{\sum_{j=1}^{n} c(f_{j}(a))}.$ (3)

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Figure 3 shows the proposed ENN model for recognition of the PD patterns. The ENN 195 developed in this work comprises several SNN architectures having the same configuration 196 but with different initial parameters. To obtain accurate values of bias and variance [22], the 197 ENN model is trained from bootstrapped resample data. Bootstrap resampling is a criterion 198 employed at the instance when the input fingerprints for the NN are limited. It is 199 implemented so as to have a number of resampled datasets that can be applied as input (i.e. 200 training) fingerprints for several NNs. With this strategy, the resampled datasets have the 201 202 same dimension as the original dataset in such a way that some samples are replicated while others are discarded. Bootstrap resampling provides an accurate value of the variance and 203

bias of the NN. This technique has been successfully applied to the ENN of various categories of data in the medical and engineering related fields and has demonstrated improved results [20,21,22].

Fig.3: The ENN model.

Among the various ENN data aggregation techniques, the dynamically weighted ensemble has been shown to outperform others in different application scenarios, e.g. in Ref [23], and therefore as a consequence this paper applies the same techniques to evaluate the SNN outputs in the ensemble. Six SNNs are applied in this work in order to have a reasonable number of diverse models to improve the generalization.

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4 PD faults analysis

This section presents the results of statistical fingerprint classification sensitivity to different 217 PR and AB resolution sizes of the $H_{qn}(\varphi)+$, $H_{qn}(\varphi)-$, $H_n(q)+$, $H_n(q)-$, $H_n(\varphi)+$ and $H_n(\varphi)-$ 218 distributions. In evaluating fingerprints for variable PR the $H_n(q)$ distributions have not been 219 considered because they do not demonstrate any statistical variation. This is expected because 220 PR change only affect the phase bins not the amplitude bins. Similarly when evaluating AB, 221 the $H_n(\phi)$ statistics have not been considered. Additionally, the sensitivity of *Q*, *cc* and *mcc* 222 were not considered, because they are found to be insensitive to different resolution sizes. For 223 *Q*, the mean discharge level is undoubtedly the same for any φ -q-n resolution changes, while 224 for *cc* the correlation of the positive and the negative half power cycles remain unchanged for 225 226 φ -*q*-*n* resolution variations.

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As an example, the influence of the change in PR and AB sizes on phase and amplitude 228 resolved patterns for surface discharge in air is shown in Fig.4. The φ -q-n patterns were 229 initially captured at 1° PR and 100 AB. Then, two approaches were implemented for data 230 transformation. First, ϕ -q-n fingerprints were captured at 1° PR and 100 AB over the 360° 231 cycle and transformed to 3°, 6°, 9°, 12° and 15° PR, keeping the AB size constant. Second, 232 based on the transformation of the φ -q-n fingerprint in the first strategy, samples having 6° 233 PR and 100AB are futher transformed to 50 AB and 25 AB, keeping the PR size constant. 234 The plots visually show that as the resolution is varied from 1° to 15° or 100 AB to 25 AB, 235 discharge numbers for each PR or AB vary resulting in potentially different statistical 236

variability of the φ -q-n patterns. For reliable statistical evaluation, 95% CI for different PR and AB sizes were obtained over large φ -q-n samples as summarised in Table 1. As an example, the 95% statistical CIs for air surface discharges and the dielectric bounded void are presented in the Appendix for different PR and AB sizes.

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242 There are three essential deductions:

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1) The *sk* and *ku* mean values and CIs of $H_n(q)$ are more sensitive to different PR sizes than AB sizes when compared to that of the *sk* and *ku* of other distributions, e.g. $H_n(\varphi)$ and $H_{qn}(\varphi)$. This is attributed to the $H_n(q)$ distributions becoming increasingly peaked as the AB sizes are reduced.

248 2) The *sk* and *ku* mean values and CIs of the $H_{qn}(\varphi)$ appear to show higher sensitivity levels 249 to different PR sizes than AB. As the PR increases, PD patterns become flatter across the 250 phase dimension resulting in statistical changes.

3) The *cc* is sensitive to different PR and AB sizes, but no defined variation trend is visible
across the various geometries considered. This is due to several factors affecting the *cc* which
varies from one PD fault to the other e.g. the discharge amplitude distribution, flatness and
peakedness of the distribution.

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Fig. 4: Processed surface discharge in air patterns.

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258 5. Application of the ENN to discriminate different PD φ-q-n resolutions 259

260 5.1 SNN and ENN training and testing approaches

To evaluate the robustness of the SNN and ENN in classifying and discriminating the statistical variations for different PR or AB sizes of the φ -q-n patterns, two strategies were implemented:

- 1) Firstly, both the SNN and ENN were trained with the 6° *PR*, 100 *AB* captured φ -q-n fingerprints and then tested with the same data, but using 3°, 12° and 15° *PR* and 100 AB. This was to determine the robustness of the SNN and ENN in capturing statistical variations arising from different PR size of the φ -q-n patterns.
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269 2) Secondly, the first strategy was repeated except that the testing was carried out with 270 25*AB* and 50AB φ -q-n data but all at 6° PR. This aims at determining whether the 271 SNN and ENN can still capture statistical variations that may arise from a different 272 *AB* resolution of the φ -q-n patterns.

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275 5.2 Statistical merit indicators for comparing the SNN and ENN 276 recognition rates

As stated in the literature [22], the major weakness of the SNN lies with its various 277 278 performance evaluation, when trained with several initial conditions (i.e. weights and biases). 279 To improve the situation, this paper applied statistical measures such as the average, variance and standard error of the mean (SEM) for the SNN and ENN comparison[15]. To obtain a 280 281 certain degree of precision on the classification outcomes and as used in a previous paper, 100 iterations were chosen for all statistical determinations[15]. This aims at developing and 282 283 comparing statistical error bound recognition eficiencies of the SNN and ENN for the various 284 φ -q-n resolution sizes.

285 5.3 Results and discussion

Similar to previous research work [1,15,24], statistical measures extracted from φ -q-n fingerprints at different resolution dimensions form the input fingerprints for SNN and ENN evaluation. To classify and discriminate these extracted statistical features, as a case study, this paper considered surface discharge in air patterns as the training set, while testing was carried out with the same surface discharge data and other PD faults of different PR and AB dimensions. Six generated φ -q-n datasets, Data 1 through to Data 6 are shown in Table 3.

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Table 3: Samples of training and testing data for the SNN and ENN

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Both the SNN and ENN were evaluated using statistical data of Data 1, Data 2, Data 3, Data 295 296 4, Data 5 and Data 6. Each set of fingerprints was composed of a matrix of size 28 rows x 17 columns. The first 15 columns were considered to be the input data, while the remaining 2 297 were the output fingerprints. The input fingerprints into the SNN and ENN are the PD 298 samples shown in Table 3, while the output parameters for the PD sample fault are chosen to 299 be [0 1], [1 0], [0 0] and [1 1]. For each PD fault data matrix, 8 rows out of 28 were selected 300 301 as the testing fingerprints for the SNN and ENN. The ENN configuration is composed of six networks with the same structure trained and tested from the 28 row vectors of bootstrapped 302

resampled data. In order to choose the best SNN set-up for the ensemble, the hidden layer,
learning and momentum rates were adjusted and optimum parameters chosen for comparison
with the SNN with these forming the configurations for the ENN. One hidden layer with 25
neurons was selected, having momentum and learning rates of 0.9 and 0.06 respectively.

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Figs. 5, 6, 7 and 8 show the classification performance of the SNN and ENN when **Data 1** is used for training and then testing undertaken with **Data 1**, **Data 2**, **Data 3** and **Data 4** respectively. Similarly, Figs. 9 and 10 demonstrate the classification result of the SNN and ENN when **Data 1** is used for training and then testing undertaking with **Data 5** and **Data 6**. From these figures, the following information have been deduced:

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1) When either the SNN or ENN is trained and tested with the same PD fault having the 314 same PR and AB size of the φ -q-n patterns, the ENN shows improved recognition 315 performance over the SNN (see Fig.5). It is obvious that μ_{E} , σ_{E} and σ_{EM} shows higher 316 317 recognition values than that of μ_S , σ_S and σ_{SM} . For the SNN and ENN trained with one PD fault and test with another, the ENN does not always produce an improved 318 recognition performance over the SNN. This is clearly demonstrated by the σ_E and σ_{EM} 319 having identical recognition intervals to σ_S and σ_{SM} , but still μ_E is greater than μ_S . 320 showing that on average the ENN has an improved recognition result in comparison to 321 322 the SNN.

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2) For the SNN and ENN trained with surface discharge in air data of one resolution size 324 and then tested with the same data having different resolution sizes (Figs. 6-10), the 325 ENN and SNN both appear to show higher average recognition probability compared to 326 the other PD faults. However, the ENN appears to be better in this case as its variance 327 intervals are always higher than any other tested PD faults (σ_E and σ_{EM} shows higher 328 recognition values than that of the $\sigma_{\rm S}$ and $\sigma_{\rm SM}$), indicating the ENN's improved 329 capability to recognize closely similar PD statistical fingerprints. This result implies 330 that even with a change in resolution sizes, it is possible to determine closely similar 331 PD fault scenarios using the SNN and the ENN. 332

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334 3) To examine the capabilities of the SNN and ENN in relation to two PR sizes of the φ -q-335 n patternsFigs. 5-8 were evaluated. The most visible change is between Figs. 5 and 8 336 i.e. when the resolution size is changed from 6° to 15°, whilst there is insignificant 337 change in the SNN and ENN recognition capabilities when the resolution size is

changed from 6° to 12° or from 6° to 3°. There is basically very little decrease in the 338 values of μ_{S} and μ_{E} that can be statistically quantified. Comparing Figs. 5 and 8 shows 339 that there is a slight decrease in the values of $\mu_{\rm S}$ and $\mu_{\rm E}$ in Fig.8 compared to that of 340 Fig.5, which appears not to be statistically significant. Generally, there is rise in the 341 values of μ_{S} , μ_{E} , σ_{E} , σ_{S} , σ_{EM} and σ_{SM} for untrained PD faults in Fig.8 when compared to 342 these parameters in Fig. 5, but the ENN parameters clearly show a rise in the statistical 343 indicators compared to the SNN. This result implies that the ENN appears to be more 344 sensitive in discriminating the 2 PRs of the φ -q-n patterns, however there exists little 345 variation in the 2 PR φ -q-n patterns applied for training and testing both the ENN and 346 SNN. 347

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To examine the performance of the SNN and ENN in capturing two AB sizes of the φ -349 4) q-n patterns, Figs. 9, 10 and 5 were compared. Generally, lower values of μ_s and μ_E are 350 visible for surface discharge in air (when compared to training and testing surface 351 discharge in air at the same resolutions or 2 PRs of the φ -q-n patterns i.e. Figs. 5-8). 352 353 The change appears to be more visible in the SNN and ENN recognition rates when the AB resolution size is changed from 100AB to 25AB rather than 50AB. For both 354 changes there is at least a 5% reduction in the recognition rates of the SNN and ENN 355 for surface discharge in air. However, when the resolution size is changed from 100AB 356 to 25AB it is obvious that σ_{E} , σ_{S} , σ_{EM} , σ_{SM} values of Fig. 10 appear to be higher than 357 those of Fig. 5 and Fig. 9. This shows a much wider correlation exists of the testing 358 data with the training data. Comparing Fig. 10 and Fig. 5 shows that the ENN has 359 higher sensitivity in statistical operator variations compared to the SNN. This results 360 implies that there exists significant variations between the training and testing data 361 caused by the change in the AB size of the φ -q-n patterns. 362

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Fig. 5. Plot of μ_S , μ_E , σ_S , σ_{E} , σ_{SM} and σ_{EM} when both SNN and ENN are trained with surface discharge in air 6° PR and 100 AB and tested with the same surface discharge and 3 other PD faults but at 6° PR and 100 AB. (μ_S and μ_E values are the centre of variances of SNN and ENN).

Fig. 6. Plot of μ_S , μ_E , σ_S , σ_{E} , σ_{SM} and σ_{EM} when both SNN and ENN are trained with surface discharge in air 6° PR and 100 AB and tested with the same surface discharge and 3 other PD faults but at 3° PR and 100 AB μ_S and μ_E values are the centre of variances of SNN and ENN).

Fig. 7. Plot of μ_S , μ_E , σ_S , σ_{E_s} , σ_{SM} and σ_{EM} when both SNN and ENN are trained with surface discharge in air 6° PR and 100 AB and tested with the same surface discharge and 3 other PD faults but at 12° PR and 100 AB (μ_s and μ_E values are the centre of variances of SNN and ENN).

Fig. 8 Plot of μ_S , μ_E , σ_S , $\sigma_{E_s} \sigma_{SM}$ and σ_{EM} when both SNN and ENN are trained with surface discharge in air 6° PR and 100 AB and tested with the same surface discharge and 3 other PD faults but at 15° PR and 100 AB (μ_S and μ_E values are the centre of variances of SNN and ENN).

Fig. 9 Plot of μ_S , μ_E , σ_S , σ_{E} , σ_{SM} and σ_{EM} when both SNN and ENN are trained with surface discharge in air 6° PR and 100 AB and tested with the same surface discharge and 3 other PD faults but at 6° PR and 50 AB(μ_S and μ_E values are the centre of variances of SNN and ENN).

Fig. 10 Plot of μ_S , μ_E , σ_S , σ_{E} , σ_{SM} and σ_{EM} when both SNN and ENN are trained with surface discharge in air 6° PR and 100 AB and tested with the same surface discharge and 3 other PD faults but at 6° PR and 25 AB (μ_S and μ_E values are the centre of variances of SNN and ENN).

388 6. Conclusions

For the majority of the PD sources considered, statistical mean CI variations exist for 389 390 different PR and AB sizes. This has been shown to be most significant in the $H_n(q)$ + and $H_{an}(\phi)$ - plots but less significant in the $H_n(\phi)$ plots. Both the SNN and ENN capabilities have 391 been tested for recognizing and discriminating resolution sizes of the φ -q-n patterns and the 392 393 results clearly show that they can detect slight changes in resolution sizes of these patterns. Additionally, the results shows that the ENN, being more capable, is more sensitive in 394 capturing several resolution changes. These results imply that for practical PD recognition 395 applications, care has to be taken not to simply train SNN or ENN with any PD φ -q-n 396 resolution data and test with another φ -q-n resolution data and expect to obtain reliable 397 results. Furthermore, since different measuring instruments may have different settings for 398 the φ -q-n patterns which are captured and stored for analysis, it is important that certain φ -q-n 399 PR and AB sizes be maintained for consistency of recognition, otherwise unreliable 400 predictions may be incurred. 401

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527 Fig. 1: Simulated PD faults a) surface discharge in air b) single void in PET c) corona in air d) surface
528 discharges in oi





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 $H_n(\varphi)$ + at 1°PR and 100 AB

 $H_n(\varphi)$ - at 1°PR and 100 AB





Fig. 5. Plot of μ_S , μ_E , σ_S , σ_{E} , σ_{SM} and σ_{EM} when both SNN and ENN are trained with surface discharge in air 6° PR and 100 AB and tested with the same surface discharge and 3 other PD faults but at 6° PR and 100 AB. (μ_S and μ_E values are the centre of variances of SNN and ENN)



570

571 Fig. 6. Plot of μ_S , μ_E , σ_S , σ_{E} , σ_{SM} and σ_{EM} when both SNN and ENN are trained with surface discharge in air 6° 572 PR and 100 AB and tested with the same surface discharge and 3 other PD faults but at 3° PR and 100 AB μ_S 573 and μ_E values are the centre of variances of SNN and ENN)

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576 Fig. 7. Plot of μ_S , μ_E , σ_S , σ_{E} , σ_{SM} and σ_{EM} when both SNN and ENN are trained with surface discharge in air 6° 577 PR and 100 AB and tested with the same surface discharge and 3 other PD faults but at 12° PR and 100 AB (μ_S 578 and μ_E values are the centre of variances of SNN and ENN)



580 Fig. 8 Plot of μ_S , μ_E , σ_S , σ_{E} , σ_{SM} and σ_{EM} when both SNN and ENN are trained with surface discharge in air 6° 581 PR and 100 AB and tested with the same surface discharge and 3 other PD faults but at 15° PR and 100 AB (μ_S

582 and μ_E values are the centre of variances of SNN and ENN)



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584 Fig. 9 Plot of μ_S , μ_E , σ_S , σ_{E} , σ_{SM} and σ_{EM} when both SNN and ENN are trained with surface discharge in air 6° 585 PR and 100 AB and tested with the same surface discharge and 3 other PD faults but at 6° PR and 50 AB (μ_S 586 and μ_E values are the centre of variances of SNN and ENN

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590 Fig. 10 Plot of μ_S , μ_E , σ_S , $\sigma_{E_s}\sigma_{SM}$ and σ_{EM} when both SNN and ENN are trained with surface discharge in air

591 6° PR and 100 AB and tested with the same surface discharge and 3 other PD faults but at 6° PR and 25 AB (μ_s 592 and μ_E values are the centre of variances of SNN and ENN)





a) sk of the 1°, 3°, 6°, 9°, 12° and 15° PR for the $H_n(\phi)$ and $H_{qn}(\phi)$ plots at 100 AB



b) ku of 1°, 3°, 6°, 9°, 12° and 15° for the $H_n(\varphi)$ and $H_{qn}(\varphi)$ plots at 100 AB



c) cc of 1°, 3°, 6°, 9°, 12° and 15° PR for the $H_n(\varphi)$ and $H_{qn}(\varphi)$ plots at 100 AB







d) sk of the 100AB, 50AB and 25AB PR for $H_n(q)$ and $H_{qn}(\varphi)$ plots at 6° PR





611 612

e) ku of the 100AB, 50AB and 25AB PR for $H_n(q)$ and $H_{qn}(\varphi)$ plots at 6° PR



cc of 100AB, 50AB and 25AB data all at 6° PR.





615



Fig. A1: The mean values and 95% CI of the mean for surface discharge in air

f)





a) sk of the 1°, 3°, 6°, 9°, 12° and 15° PR for the $H_n(\varphi)$ and $H_{qn}(\varphi)$ plots at 100 AB







b) ku of the 1°, 3°, 6°, 9°, 12° and 15° PR for the $H_n(\varphi)$ and $H_{qn}(\varphi)$ plots at 100 AB



d)

c) cc of 1°, 3°, 6°, 9°, 12° and 15° PR for the $H_n(\varphi)$ and $H_{qn}(\varphi)$ plots at 100 AB







e)

sk of the 100AB, 50AB and 25AB PR for $H_n(q)$ and $H_{qn}(\varphi)$ plots at 6° PR





f) cc of 100AB, 50AB and 25AB data all at 6° PR.

637 Fig. A2: The mean values and 95% CI of the mean for single void in PET

- **<u>Tables:</u>**

641 Table 1: PD fault types with the test voltages and corresponding φ -q-n samples.

PD fault type	Test voltage	φ -q-n samples generated
Corona in air	1.5 kV, 1.9 kV, 2 kV and 2.2 kV for the 5 mm gap and 1.7 kV, 1.9 kV, 2.3 kV and 2.8 kV for the 10 mm gap distance	42
Surface discharge in air	5 kV	148
Surface discharge in oil	18.5 kV	90
Void in the insulation	2.7 kV	169

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Table 2: Mathematical expressions of statistical fingerprints

Statistical	Mathematical equation
operator	
operator	
Skewness	$sk = \frac{\sum (x_j - \mu)^3 P_j}{\sigma^3}$
Kurtosis	$ku = \frac{\sum (x_j - \mu)^4 P_j}{\sigma^4}$
	$Q_s^-/$
Discharge	$O = \frac{N_s}{N_s}$
Enotor	$\boldsymbol{\mathcal{Z}} \qquad \boldsymbol{\mathcal{Q}}_{\boldsymbol{\mathcal{S}}}^{+} / \boldsymbol{\mathcal{A}}_{\boldsymbol{\mathcal{X}}}^{+}$
racioi	/ N _S
Cross- correlation	$cc = \frac{\sum x_{j} y_{j} - \frac{\sum x_{j} \sum y_{j}}{n}}{\sqrt{\left[\sum x_{j}^{2} - \frac{(\sum x_{j})^{2}}{n}\right] \left[\sum y_{j}^{2} - \frac{(\sum y_{j})^{2}}{n}\right]}}$

Table 3: Samples of training and testing data for the SNN and ENN

Samples	Description	
Data 1	surface discharge in air φ -q-n data at 6° PR and 100 AB	
Data 2	surface discharge in air and 3 other PD faults φ -q-n data, all at 3° PR and	
	100AB	
Data 3	surface discharge in air and 3 other PD faults φ -q-n data, all at 12° PR and	
	100AB	
Data 4	surface discharge in air and 3 other PD faults φ -q-n data, all at 15° PR and	
	100AB	
Data 5	surface discharge in air and 3 other PD faults φ -q-n data, all at 6° PR and 50	
	AB.	
Data 6	surface discharge in air and 3 other PD faults φ -q-n data, all at 6° PR and 25	
	AB.	